

Nanostrukturen-Herstellung

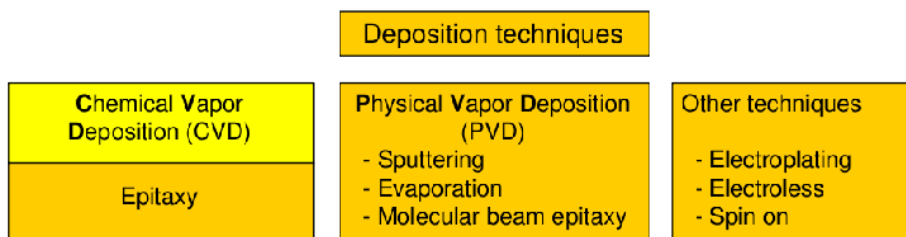
Chemical Vapor deposition (CVD)

PECVD, LPCVD, APCVD, RTP, CCSVT, OVPD, MOCVD,....

- **CVD Principle & Parameter**
- **Deposition of Chalcopyrites**
 - CVD
 - CCSVT
 - MOCVD
- **Organic Solar cells**
 - OVPD

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Classification of deposition techniques



General requirements to the processes:

- Low cost of ownership
- high throughput

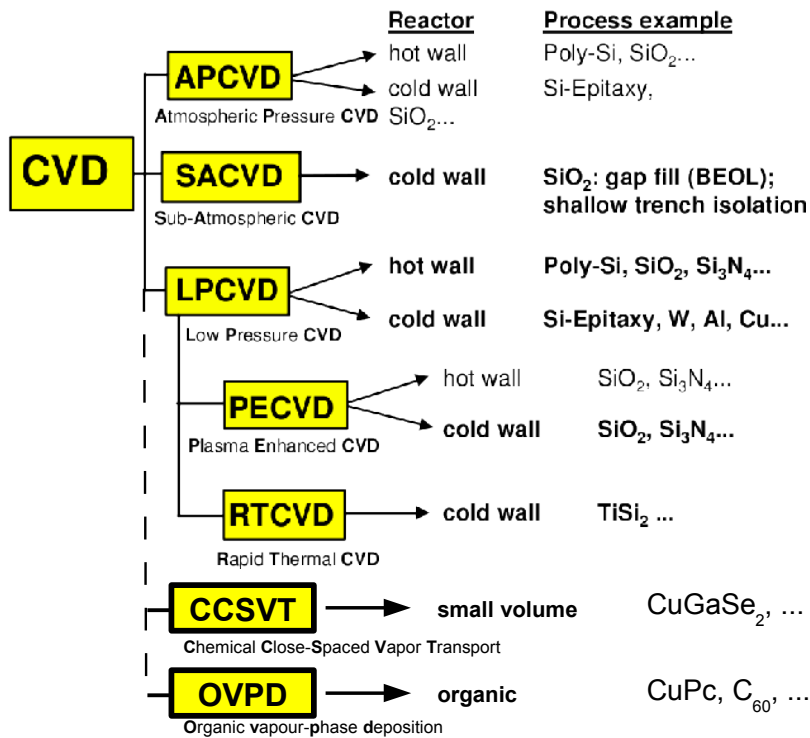
to the films:

- good thickness uniformity
- high purity and density
- controlled composition and stoichiometry
- high degree of structural perfection
- good electrical properties
- excellent adhesion
- good step coverage

Advantages of CVD:

- high purity deposits and very good step coverage can be achieved
- great variety of materials and chemical compositions
- some films cannot be deposited with good properties by other methods
- good economy and process control are possible for many films

Classification and application of CVD techniques

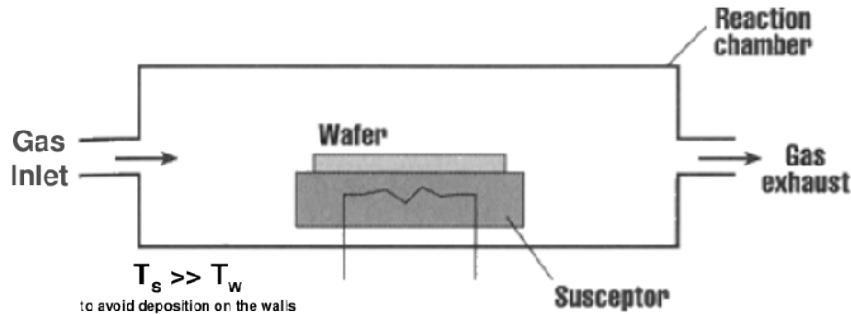


Basics of Chemical Vapor Deposition

- CVD is extremely popular
 - preferred deposition method for wide range of materials
- Simple thermal process
 - modifications also provide alternate energy sources such as plasma or optical excitation to drive chemical reactions even at low temperature
- Allows coverage of high aspect ratio features
 - especially in submicron technologies with very small contacts
- Well suited to deposition of insulating or semiconducting films
 - thin films based on chemical reactions

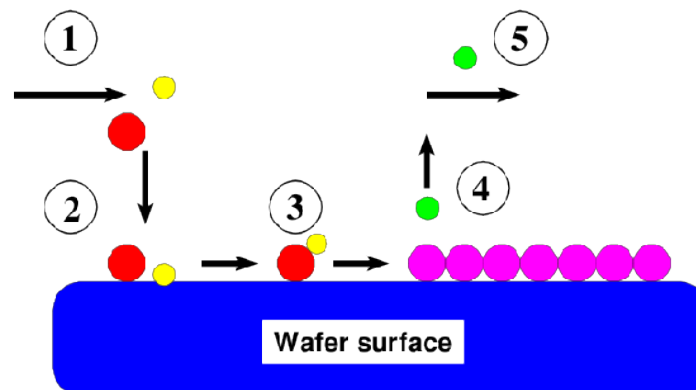
Simple CVD System for Silicon Deposition

A simple prototype thermal CVD reactor



- used for the decomposition of silane gas to form polycrystalline silicon
- while the gas flows from left to right the silane starts to decompose when it approaches the hot susceptor
- in order to fight the decreasing silane concentration the gas is diluted in hydrogen
- the flow is slow enough that the pressure in the chamber can be considered uniform

Theoretical background: Elementary processes

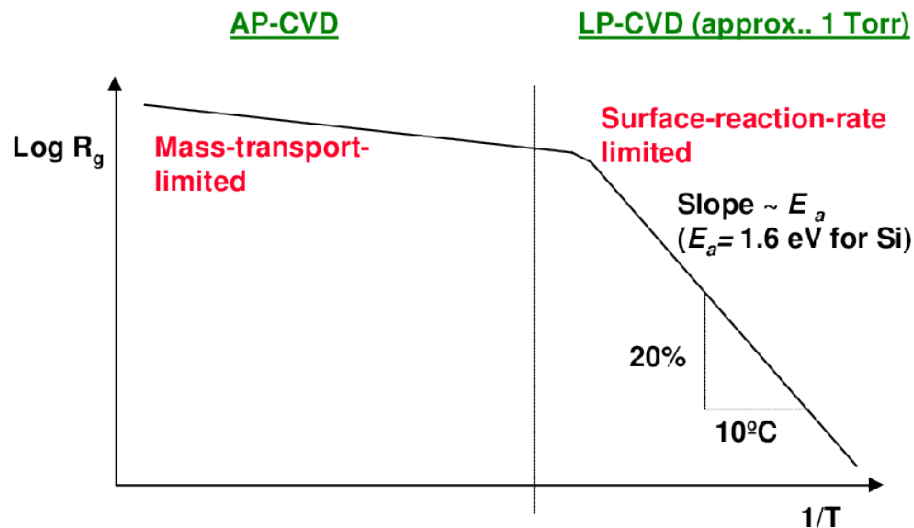


- 1 Transport of the precursor(s) with the carrier gas to the reaction chamber and to the wafer surface (convection and diffusion)
- 2 Adsorption or chemisorption of the precursor(s) at the wafer surface
- 3 Chemical surface reaction (including dissociation and surface diffusion)
- 4 Film growth, desorption of volatile reaction products, transport of reaction products away from the wafer surface (diffusion)
- 5 transport of reaction products with the carrier gas out of the reactor

Variables to be Controlled

- Deposition process includes:
 - force convection
 - boundary-layer diffusion
 - surface absorption
 - decomposition
 - surface diffusion
 - incorporation
- **Variables to be controlled for film properties**
 - **Temperature**
 - **Pressure**
 - **Flow Rate**
 - **Position**
 - **Reactant Ratio**

Deposition Rate Limits

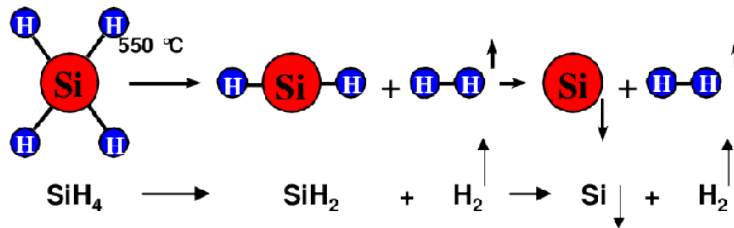


The aforementioned steps are sequential, hence the one that occurs at slowest rate will determine the deposition rate.
These rate-determining steps can be grouped into **gas-phase** processes and **surface** processes.

Theoretical background: Reaction types

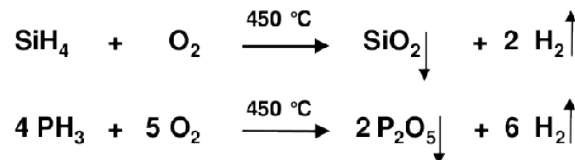
Pyrolysis: Thermal decomposition of gaseous species (hydrides, carbonyls, organometallic compounds) on hot substrates

→ Example: *LPCVD of polycrystalline or amorphous silicon films*



Oxidation: CVD of SiO_2 and glasses by reaction of gaseous hydrides or halides of Si and dopants with oxygen or oxygen-containing compounds

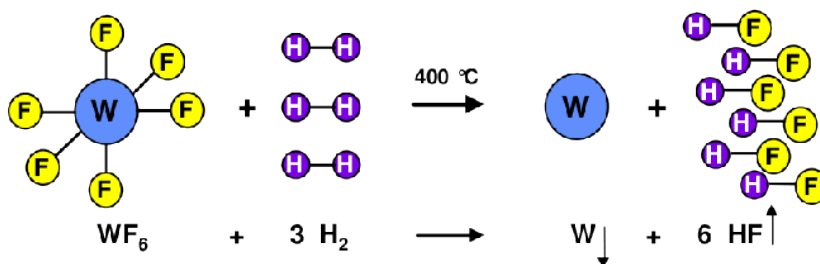
→ Example: *LPCVD of PSG*



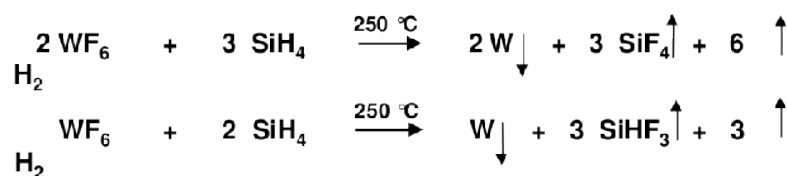
Theoretical background: Reaction types

Reduction: Reaction of halides or oxygen-containing compounds with hydrogen or hydrogen-containing compounds to generate solid deposits and gaseous byproducts

→ Examples: *LPCVD of Tungsten, blanket deposition*

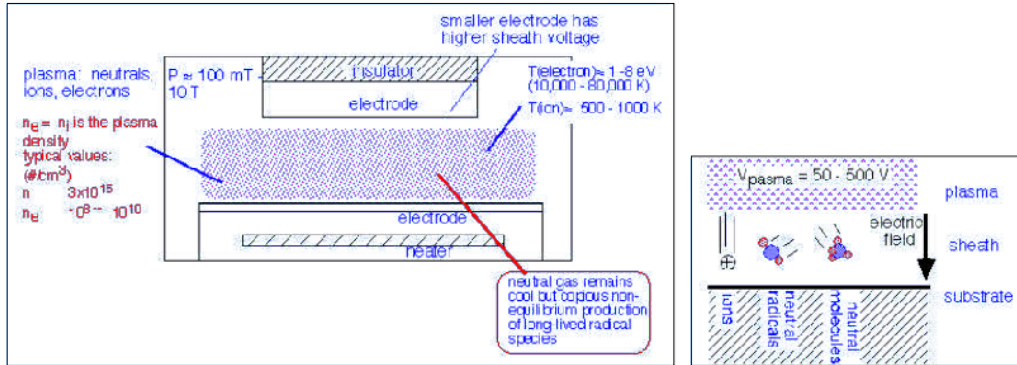


LPCVD of Tungsten, selective deposition



PECVD (Plasma Enhanced CVD)

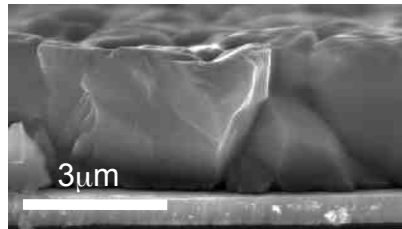
PECVD Reactor; parameter



| | | | |
|--------------|------------------|--------------------|------------------------|
| gas flow: | 10...10.000 sccm | electrode spacing: | 10...100 mm |
| pressure: | 0.5...15 Torr | rf power: | 100...1.000 W |
| temperature: | 300...550 °C | rf frequency: | 13.56 MHz, 400 kHz ... |

CuGaSe₂ in solar cells

- Cu(In,Ga)Se₂ (CIGS) in thin film solar cells
- High quality cells (polycrystalline)
- **efficiency >20%**
- Many properties not understood yet (why is it good, loss mechanisms, defects...)

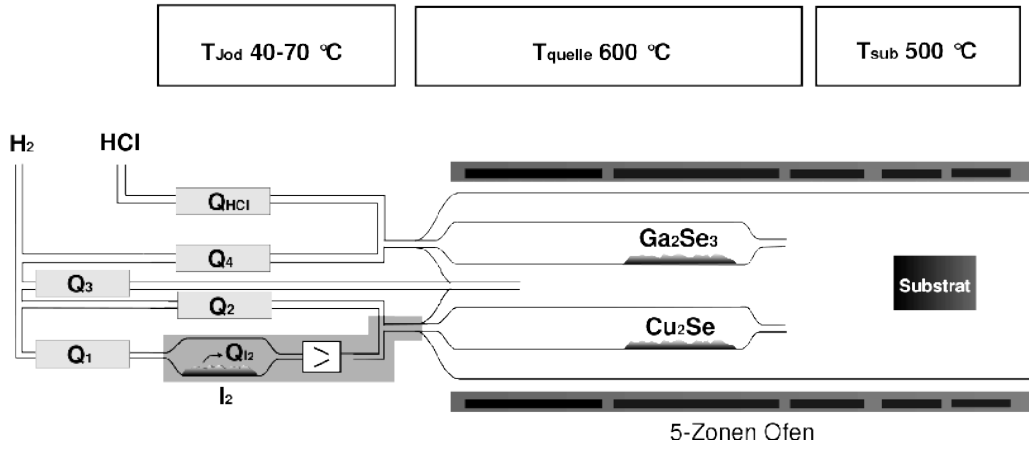


→ Analysis is difficult (polycrystalline absorber)

Single crystalline thin films for fundamental analysis needed

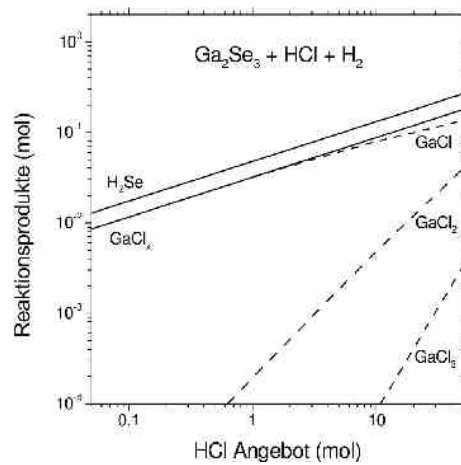
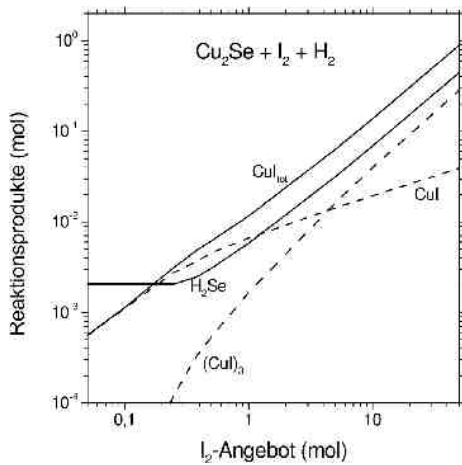
→ **epitaxial CuGaSe₂ layers**

CVD of CuGaSe_2



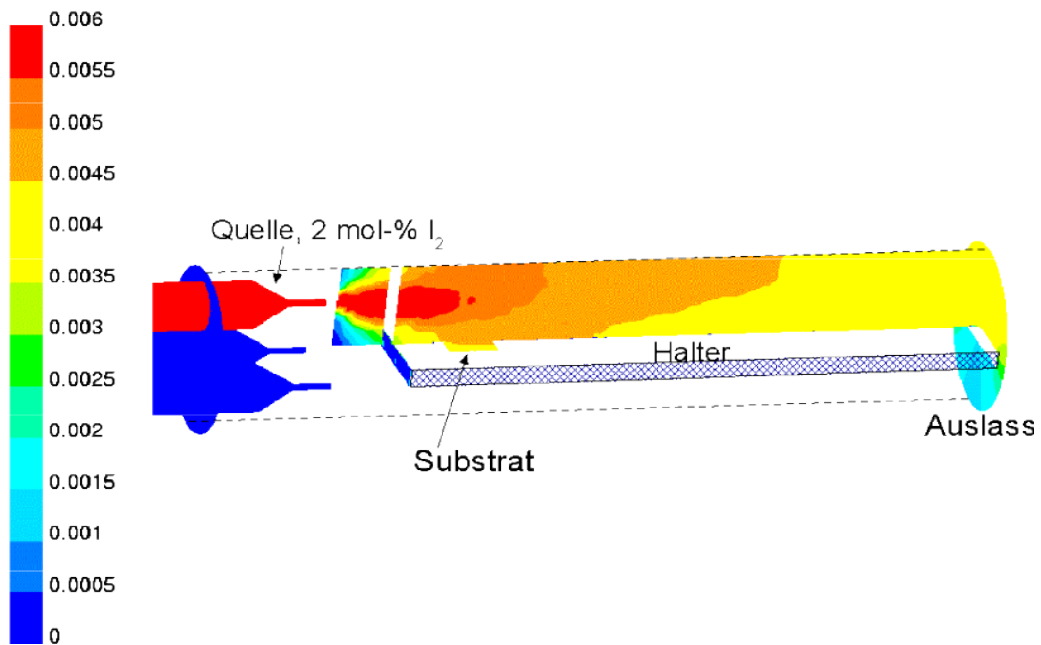
PhD Thesis, D. Fischer 2000, FU-Berlin

Reaction Products



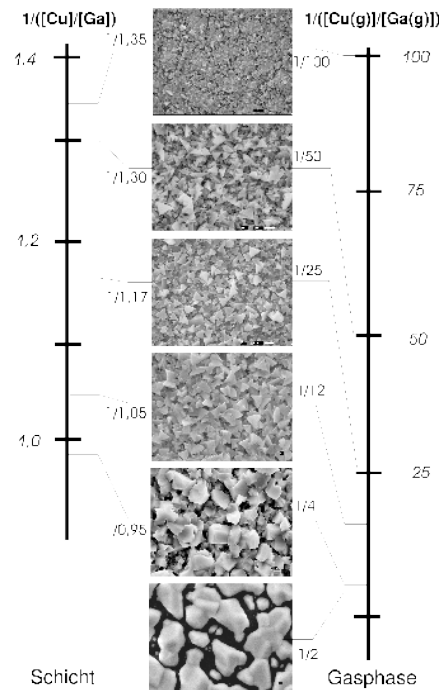
PhD Thesis, D. Fischer 2000, FU-Berlin

CVD gas steam, I₂ concentration

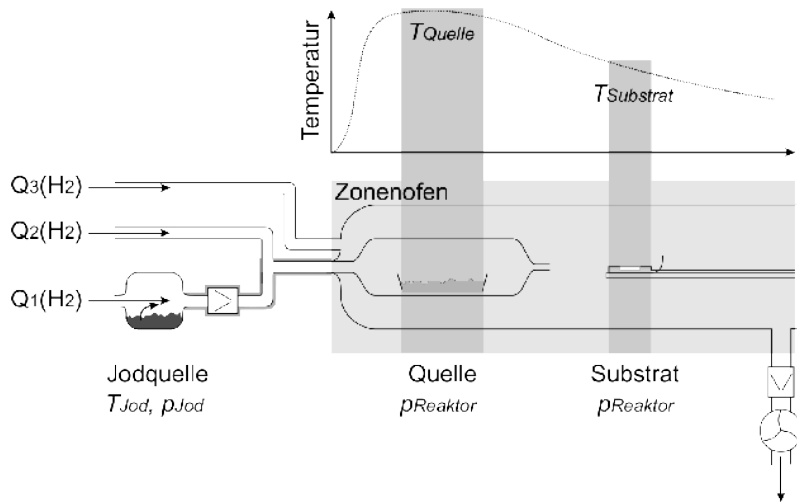
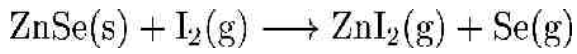


PhD Thesis, D. Fischer 2000, FU-Berlin

Film Composition & Structure



CVD of ZnSe



PhD Thesis, A. Rumberg 2001, FU-Berlin

ZnSe buffer layer for CuGaSe₂ solar cells

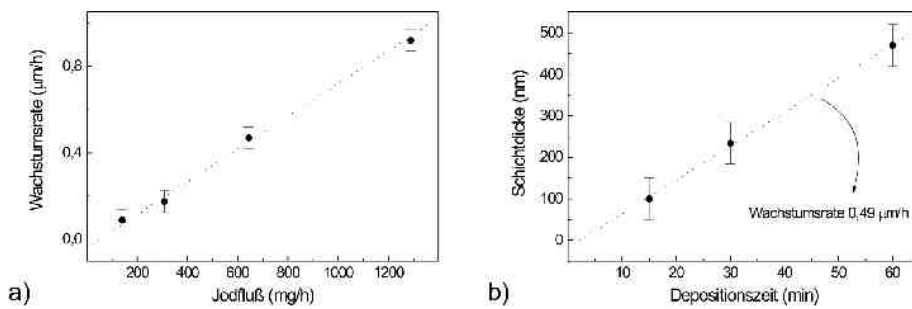
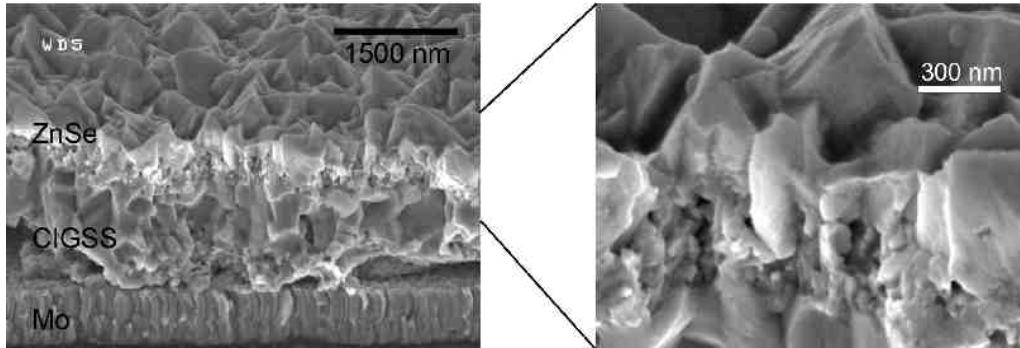


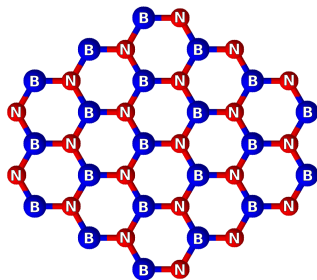
Abbildung 5.1: a) ZnSe Wachstumsrate als Funktion der Jodtransportrate, b) Schichtdicke über der Depositionszeit, jeweils korrigiert um die Dicke der Keimschicht (100 nm) (Quellen-/Substrattemperatur 550/350 °C)

PhD Thesis, A. Rumberg 2001, FU-Berlin

ZnSe buffer layer for CuGaSe₂ solar cells



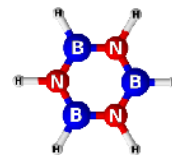
Hexagonal Boron Nitride on Rh(111)



Exposure of Borazine (H₆B₃N₃) vapour to the rhodium (111) surface

Parameters:

$T_{\text{sample}} = 520^{\circ}\text{C}$
 $p_{\text{borazine}} = 3 \times 10^{-8} \text{ mbar}$
 $t_{\text{borazine}} = 3 \text{ min}$



- 3 different height areas are formed
- Mesh periodicity: $\sim 3.2 \text{ nm}$
- Holesize: $\sim 2 \text{ nm}$
- Binding Energy
 - poreside: 0.49 eV
 - wireside: -0.04 eV



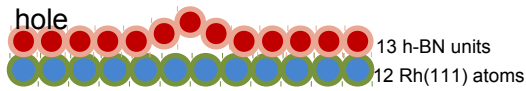
[1] M. Corso et al., Science 303, 217 (2004)

[2] Laskowski et al., Phys. Rev. Lett. 98, 106802 (2007)

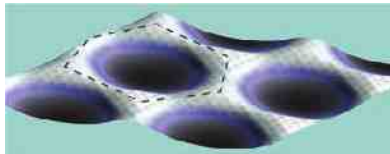
[3] Laskowski et al., J. Phys.: Cond. Mat., 20, 064207 (2008)

Sample Preparation

h-BN on Rh(111)

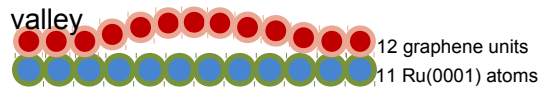


Exposure of borazine on a Rhodium (111) surface @ 520°C

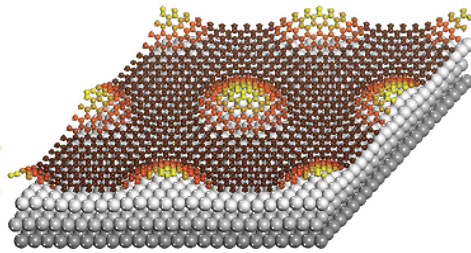


M. Corso et al., Science 303, 217 (2004)
Laskowski et al., Phys. Rev. Lett. 98, 106802 (2007)
Laskowski et al., J. Phys.: Cond. Mat., 20, 064207 (2008)
H. Dil et al., Science 319, 1824-1826, (2008)

Graphene on Ru(0001)

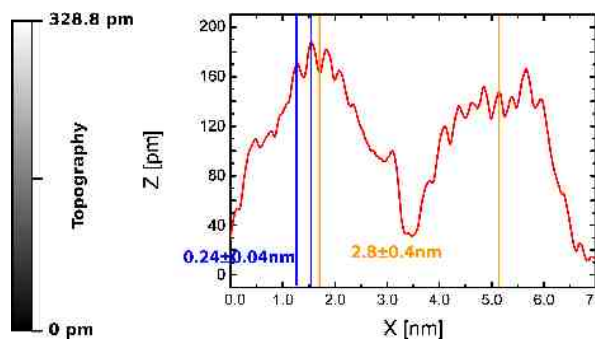
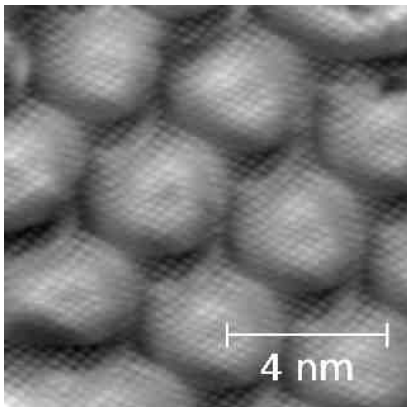


Exposure of ethylene on a Ru(0001) surface @ 1000°C for 10min



S. Marchini et al. Phys. Rev. B 76, 075429, (2007)
D. Martocchia et al. Phys. Rev. Lett. 101, 126102, (2008)
W. Moritz et al., Phys. Rev. Lett. 104, 136102, (2010)
A. L. Vazquez de Parga et al., Phys. Rev. Lett. 100, 056807, (2008).

h-BN High Resolution nc-AFM at RT



- hole – wire distance ~2.8nm
- BN unit cell distance ~240pm
- high resolution only with inverted contrast!?

$$\Delta f_{1st} = -180\text{Hz}, A_{1st} = 6\text{nm}, V_{AC} = 500\text{mV}$$

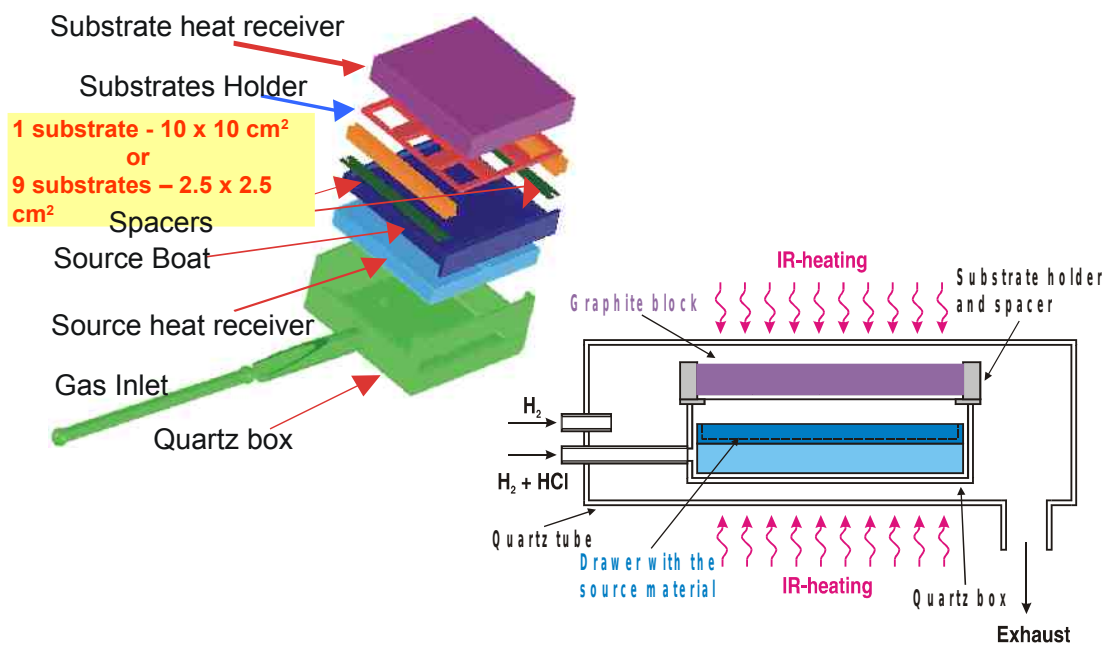
Chemical closed-space vapor transport (CCSVT)

Benefits for CuGaSe_2 deposition:

- Taking advantage of the CVT and closed -space vapor transport (CSVT) techniques, namely, fast volatilization of source materials by reaction with halogens such as molecular I_2 , Cl_2 or HCl to gaseous halogenides which occurs at significantly lower temperatures
- Using III-VI compounds exhibiting low sublimation temperatures in combination with copper-selenides and -sulfides
- Employing advantages of the rapid thermal processing (RTP), thermal annealing of the metal precursors deposited on large areas

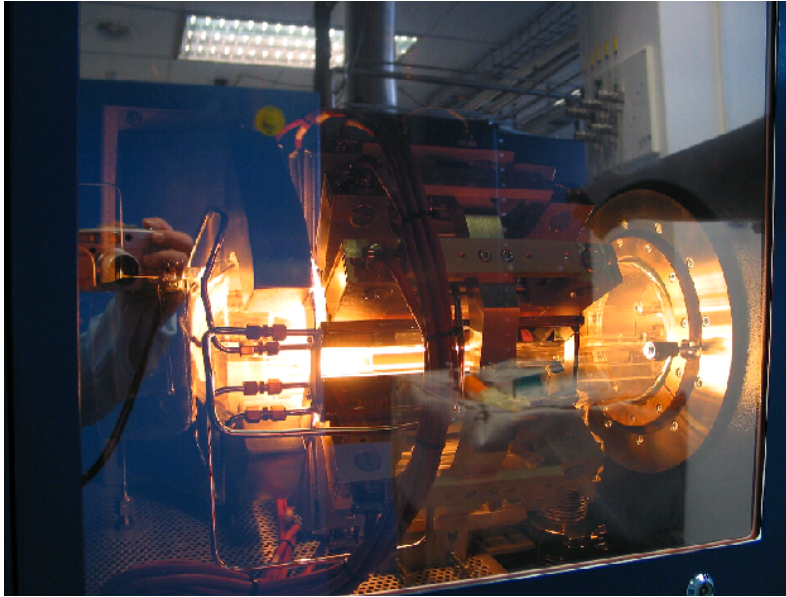
Thin Solid Films 451 – 452 (2004) 556–561

CCSVT Apparatus



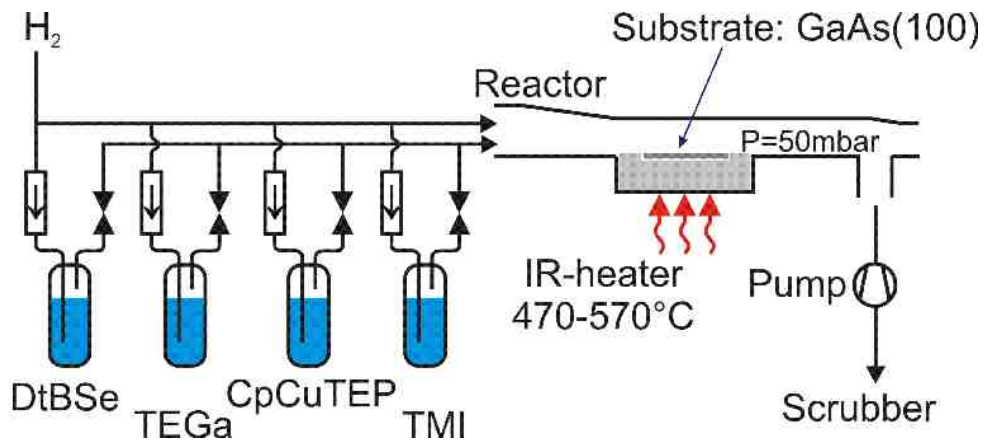
Thin Solid Films 451 – 452 (2004) 556–561

CCSVT Apparatus



MOCVD, Metalorganic Chemical Vapor Deposition

MOVPE (Metalorganic vapor phase epitaxy)



MO precursors for Cu, Ga, Se:

- CpCuTEP Cyclopentadienyl-Copper-Triethylphosphine
- TEGa Triethylgallium
- DtBSe Ditertiarybutylselenide

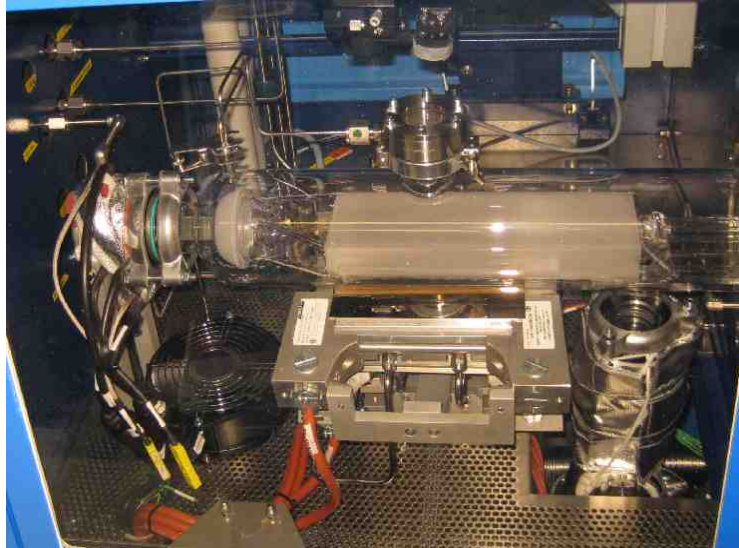
The MOVPE process

System: Aixtron AIX 200 (2" wafer)

Pressure: 50mbar

Temperature: 570°C

Substrate: GaAs (100)



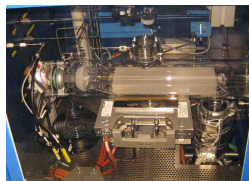
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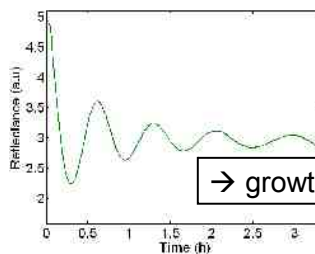
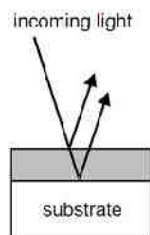
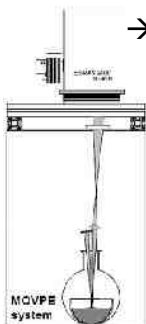


MO precursors for Cu, Ga, Se:

- CpCuTEP Cyclopentadienyl-Copper-Triethylphosphine
- TEGa Triethylgallium
- DtBSe Ditertiarybutylselenide

In-situ monitoring: EpiRas - Laytec

→ RAS + Reflectance



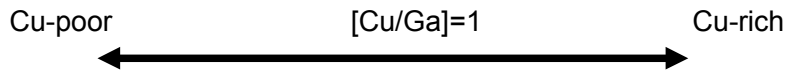
→ growth rate ≈ 100nm/h

1. Reflection at surface → roughness
2. Fabry-Perot oscillations → thickness

CuGaSe₂ with various compositions

CuGaSe₂ still forms under strong deviations from [Cu/Ga]=1

From phase diagram:



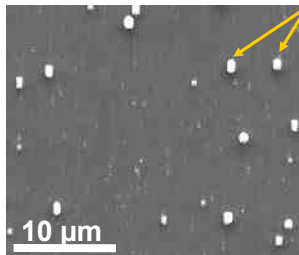
Cu-poor CuGaSe₂ ([Cu/Ga] < 1)

Stoichiometric CuGaSe₂ ([Cu/Ga] = 1)
+ secondary phase: Cu_xSe

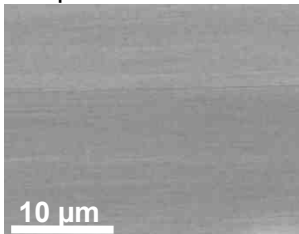
Co-existing phases, what happens during growth?

CuGaSe₂ grown under various [Cu/Ga] ratios

Cu-rich
Cu_xSe crystals



Cu-poor



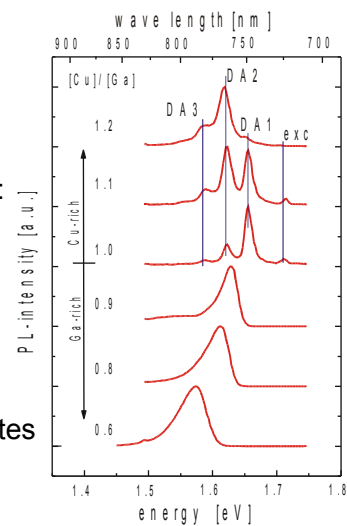
PL depends on Cu/Ga ratio:

Cu-rich PL shows:

- Donor-Acceptor transitions
- Excitonic transitions

Cu-poor:

- Transitions from defect states

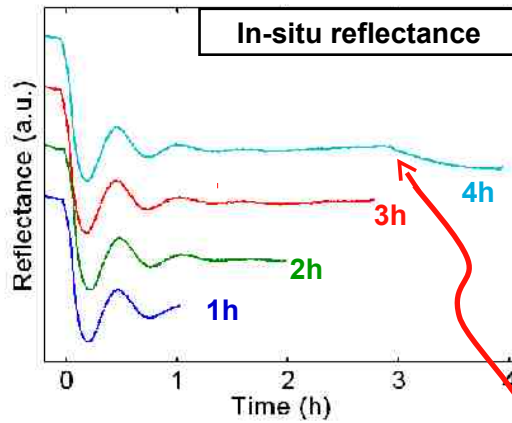
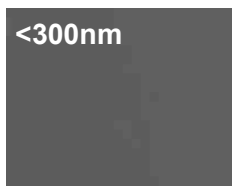
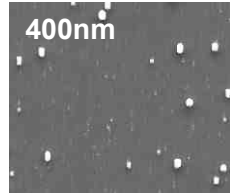


[Bauknecht, A., Siebentritt, S., Albert, J., Lux-Steiner, M. C., J. Appl. Phys., 89 (2001) 4391-4400]

Analyzing time evolution of two phase system

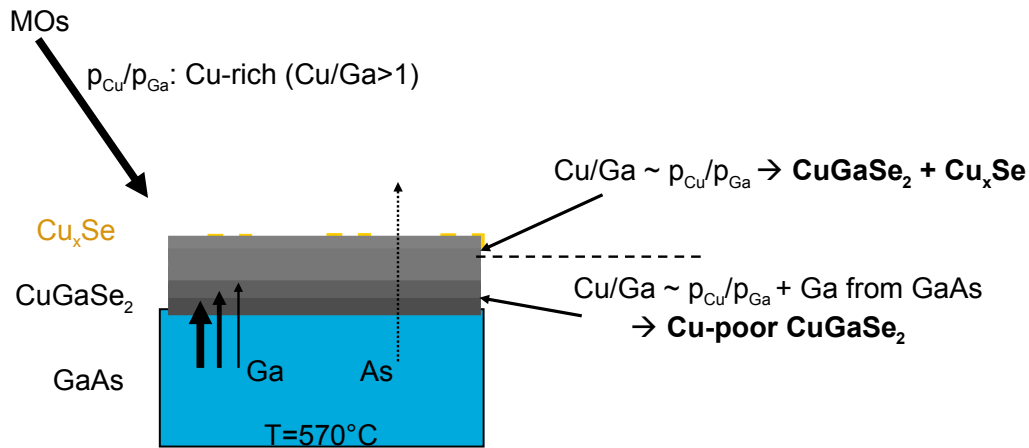
Time evolution of secondary phase Cu_xSe :

Cu-rich standard recipe (4h = 400nm) was stopped at 1h...4h



No Cu_xSe on short runs! Appear at 3→4h, **WHY?!**

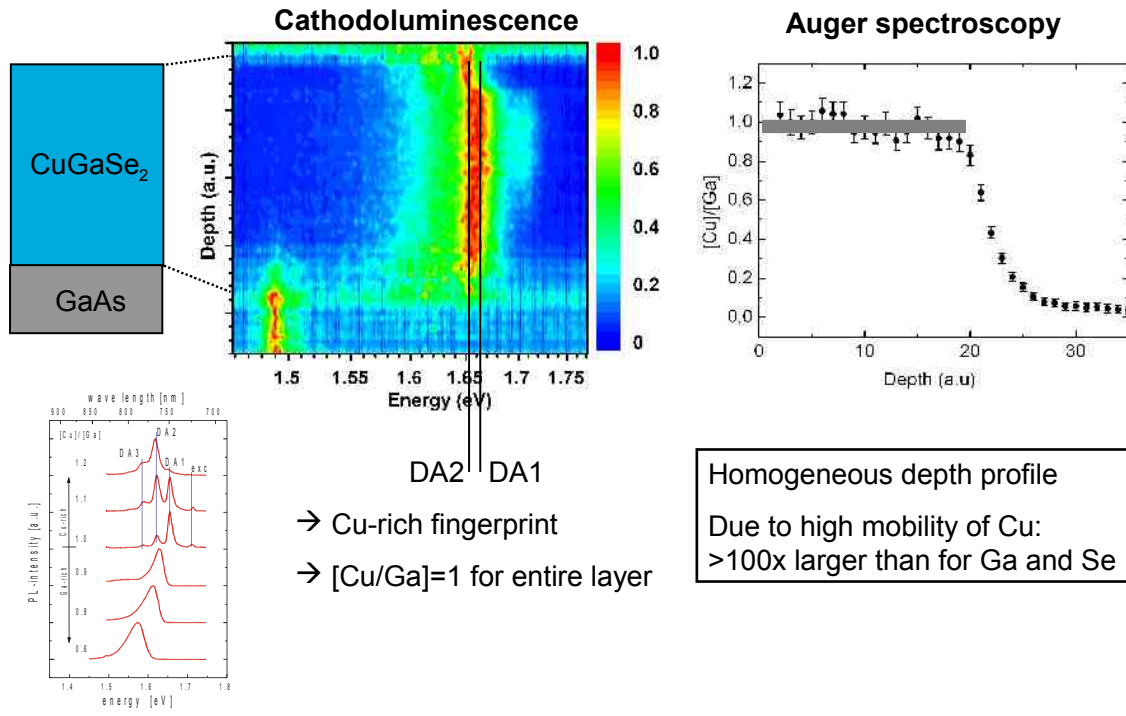
Proposed growth model



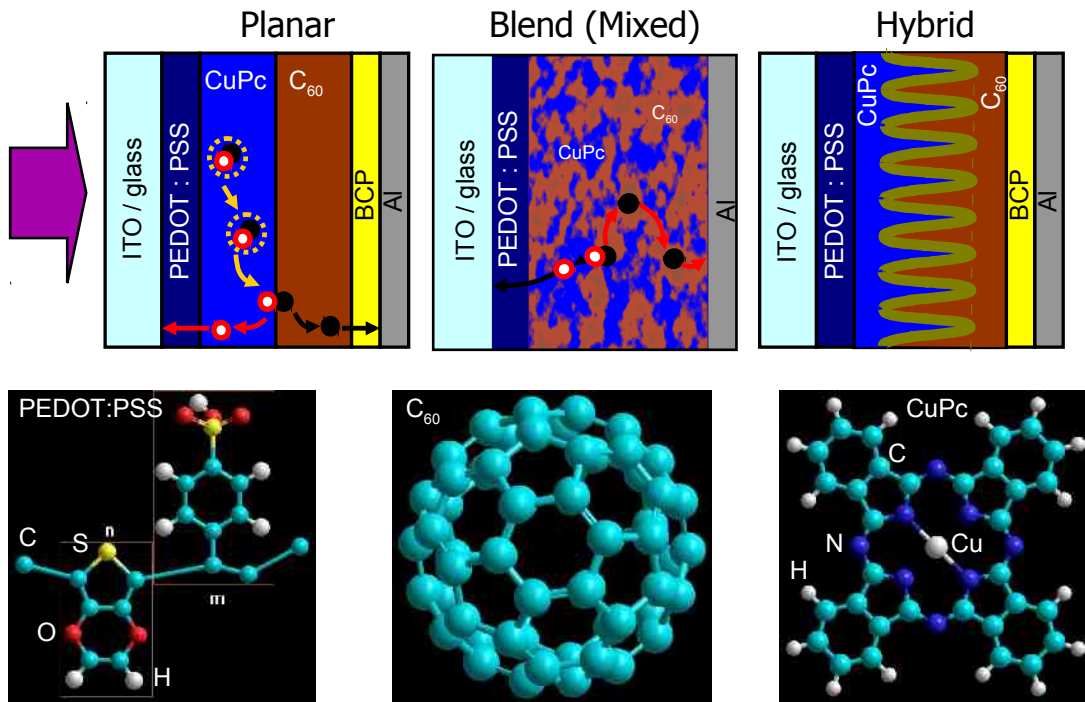
1. Cu-poor CuGaSe_2
2. stoichiometric $\text{CuGaSe}_2 + \text{Cu}_x\text{Se}$

→ Gradient in composition profile?

Depth profile of [Cu/Ga]-ratio

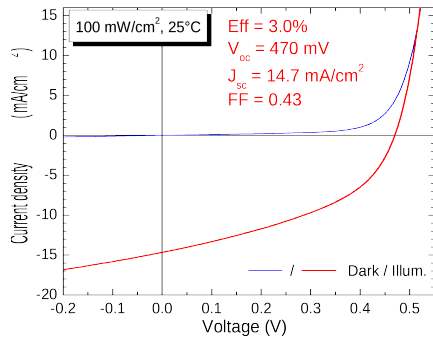
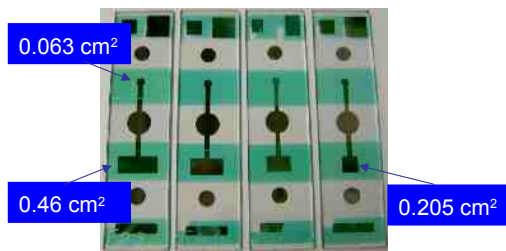


Organic Solar Cells



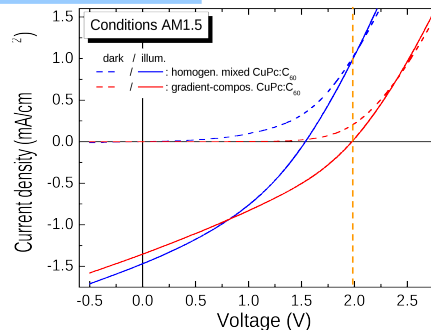
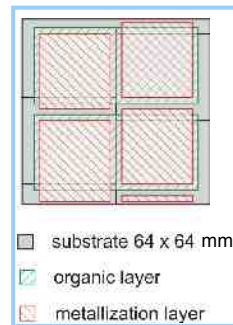
Device concepts & achievements

Organic solar cells



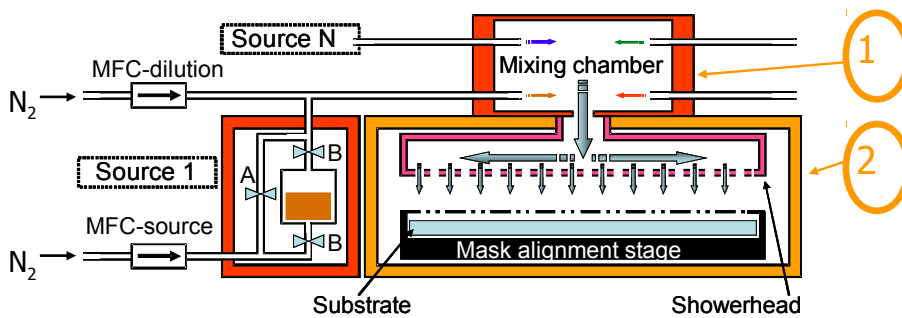
¹M. Rusu *et al.*, *Thin Solid Films* 516 (2008) 7160.
²M. Rusu *et al.*, Springer special issue (2009).

First PV mini-modules

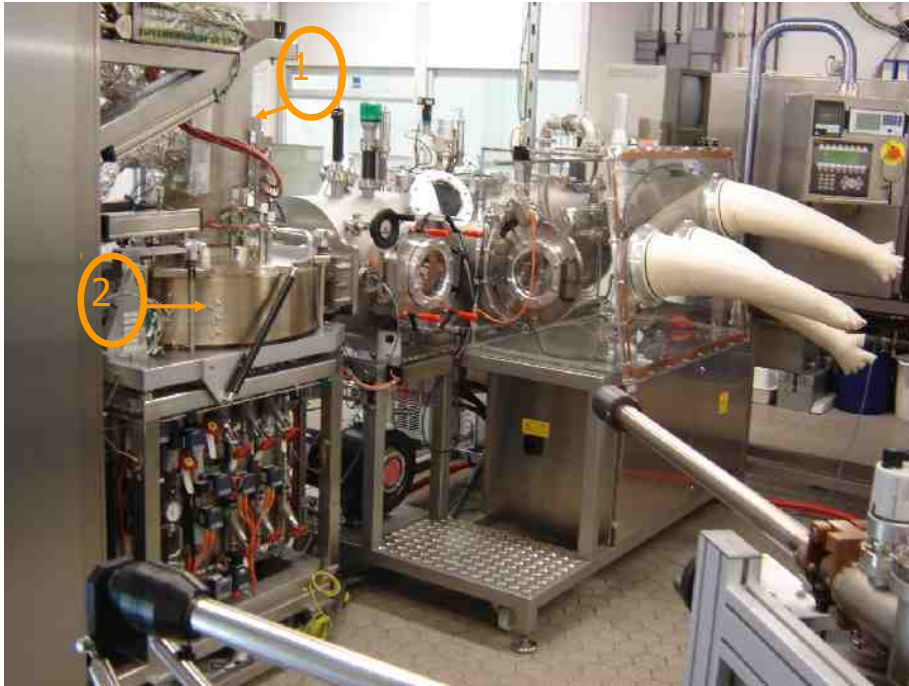


¹M. Rusu *et al.*, *23rd EUPVSEC*, WIP-Renewable Energies, ISBN: 3-936338-24-8, 2008, p. 679-681.

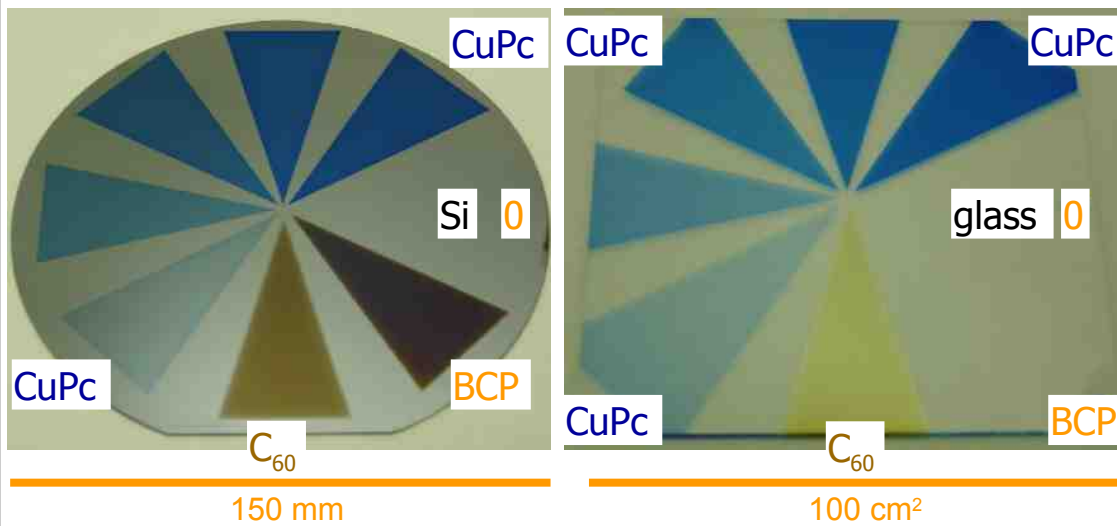
Organic vapor phase deposition - OVPD



¹M. Rusu *et al.*, *Renewable Energy* 33 (2008) 254.

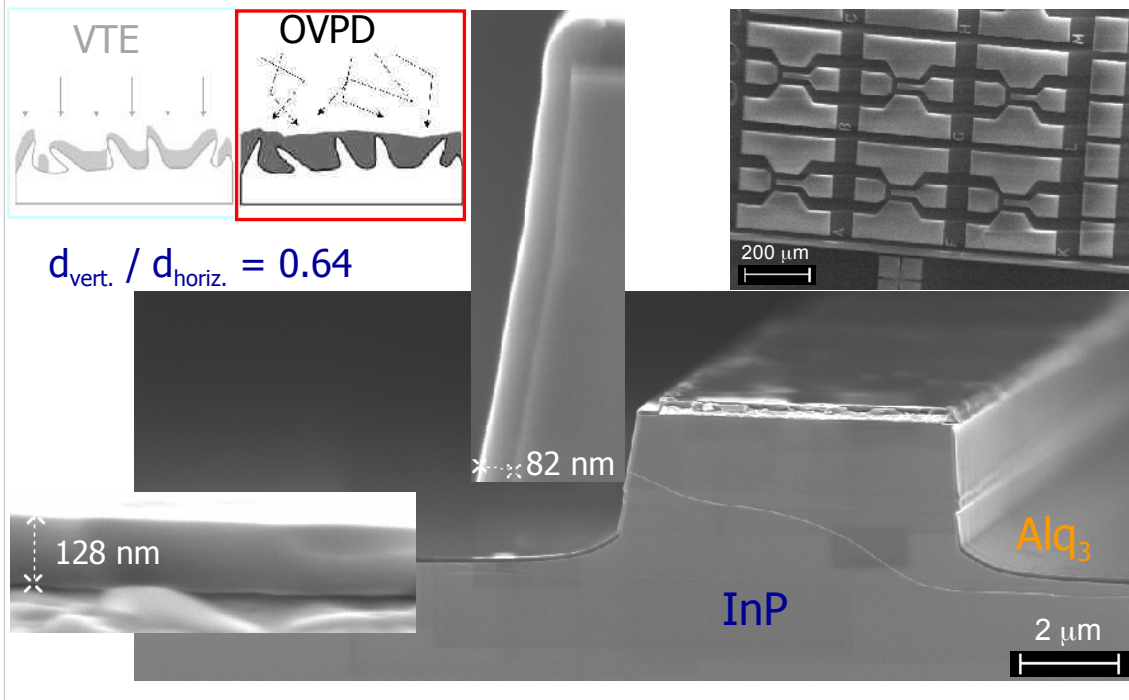


CuPc, C₆₀ and BCP by OVPD

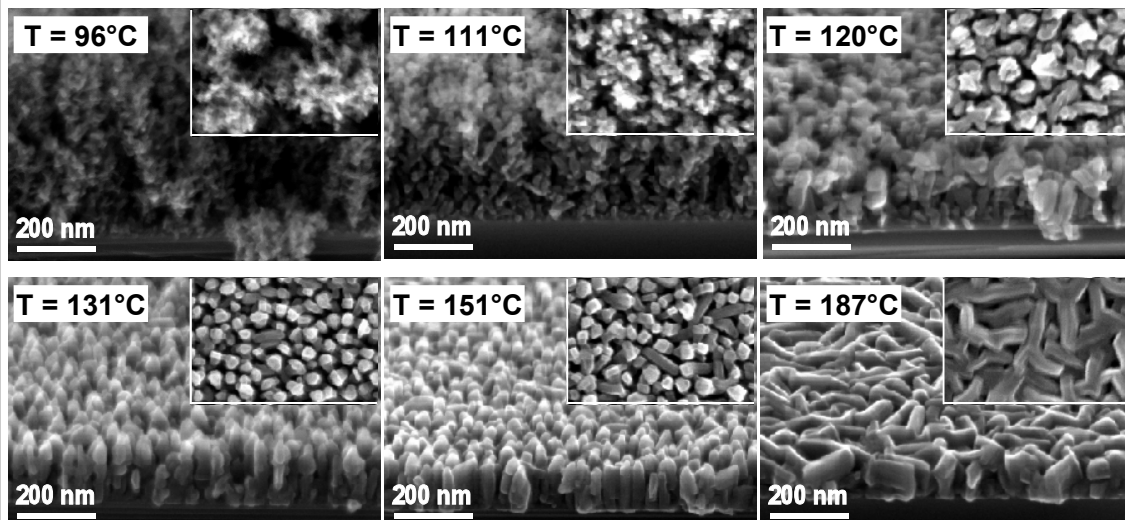


- Homogeneous deposition
 - Deposition areas show sharp edges
 - No 'memory' effects are observed
 - Deposition process reproducible

OVPD: Prove of the diffusion-controlled process



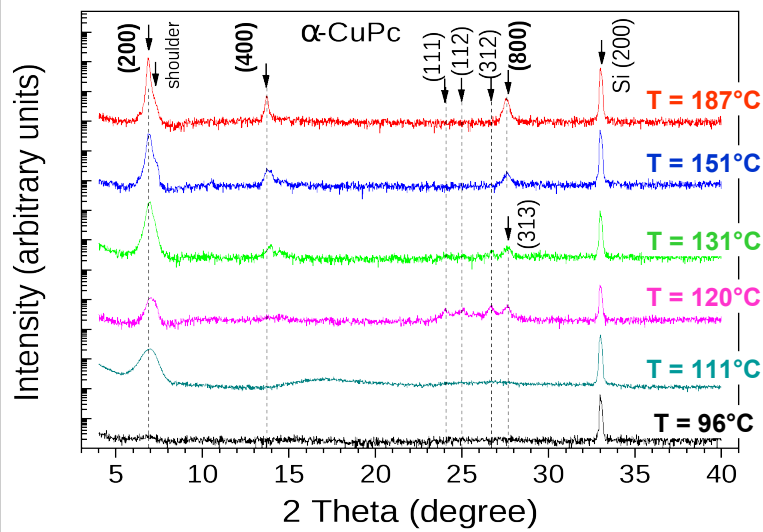
CuPc layers on Si<100>



CuPc film structure develops through a coalescence process

Columnar and elongated rod-like crystallites

Crystallite dimensions and spacing comparable to the excitons diffusion length



Elevated substrate temperature enhances the $\langle 100 \rangle$ preferential orientation of the monoclinic α -CuPc polymorph

